## Special Issue

# Surface Technology: Laser in Trace Analysis and Precision Measurements

### Message from the Guest Editors

We are inviting submissions to the Special Issue on Laser Application in Trace Analysis and Precision Measurements. Through the interaction of laser with molecules, atoms, and nucleus, the trace analysis and precision measurements technologies of physical and chemical material are formed, which have great application prospects in the frontier fields of biology, geology, energy, environment, space, and so on. In recent years, facing the new requirement brought by the development of advanced manufacturing of precision measurement, scientific research institutions have engaged in in-depth scientific researches on common issues of principle and method for measuring system. In addition, in the field of laser application, the breakthroughs on trace analysis and precision measurements formed novelty measuring theory, method, and instrument. In this Special Issue, we invite submissions exploring cutting-edge research and recent advances in the fields of laser application in trace analysis and precision measurements.

- new theory and principle
- method and technology
- key component development
- measuring instrument
- data evaluation and processing
- laser application

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### Guest Editors

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### Deadline for manuscript submissions

closed (31 October 2023)

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## Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

## Editor-in-Chief

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